

## ABSTRACT OF THE DISCLOSURE

There is provided an apparatus and a method for automatically generating patterns including a pattern applied for a path that influences crosstalk to a measurement path, in a delay test using a scan path to make measurement of the effect of the path that influences crosstalk to the measurement path possible. An adjacent path extraction process 102 is performed on the basis of layout information on a semiconductor integrated circuit so as to extract information on a path that influences crosstalk, with reference to crosstalk information, a measurement path extraction process (106) is performed, so that information on an aggressor path that influences crosstalk to the measurement path of a combinational circuit between flip-flops that constitutes the scan path is generated, and then, on the basis of circuit information (108), and information (107) on the measurement path and the aggressor path, a Delay\_test ATG (109) generates delay test patterns (110), including a pattern for outputting a signal for measuring a delay from a flip-flop associated with the measurement path and a pattern for outputting a signal that influence crosstalk to the measurement path from a flip-flop associated with the aggressor path.